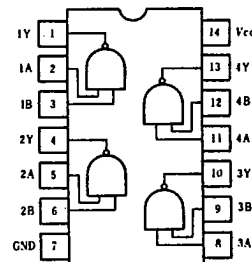


HD74ALS01 • Quadruple 2-Input Positive NAND Gates (with open collector outputs)

T-43-15

PIN ARRANGEMENT



(Top View)

ELECTRICAL CHARACTERISTICS ($T_a = -20 \sim +75^\circ\text{C}$)

Item	Symbol	Test Conditions	min	typ*	max	Unit
Input voltage	V_{IH}		2.0	—	—	V
	V_{IL}		—	—	0.8	V
Output voltage	V_{OL}	$V_{CC}=4.5\text{V}, V_{IH}=2\text{V}, I_{OL}=4\text{mA}$	—	—	0.4	V
		$V_{CC}=4.75\text{V}, V_{IH}=2\text{V}, I_{OL}=8\text{mA}$	—	—	0.5	V
Output current	I_{OH}	$V_{CC}=4.5\text{V}, V_{IL}=0.8\text{V}, V_{OH}=5.5\text{V}$	—	—	100	μA
Input current	I_{IH}	$V_{CC}=5.5\text{V}, V_I=2.7\text{V}$	—	—	20	μA
	I_I	$V_{CC}=5.5\text{V}, V_I=7\text{V}$	—	—	0.1	mA
	I_{IL}	$V_{CC}=5.5\text{V}, V_I=0.4\text{V}$	—	—	-0.2	mA
Supply current	I_{CCH}	$V_{CC}=5.5\text{V}, V_I=0\text{V}$	—	0.43	0.85	mA
	I_{CCL}	$V_{CC}=5.5\text{V}, V_I=4.5\text{V}$	—	1.62	3.00	mA
Input clamp voltage	V_{IK}	$V_{CC}=4.5\text{V}, I_{IN}=-18\text{mA}$	—	—	-1.5	V

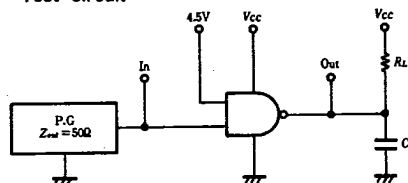
* $V_{CC}=5\text{V}, T_a=25^\circ\text{C}$

SWITCHING CHARACTERISTICS

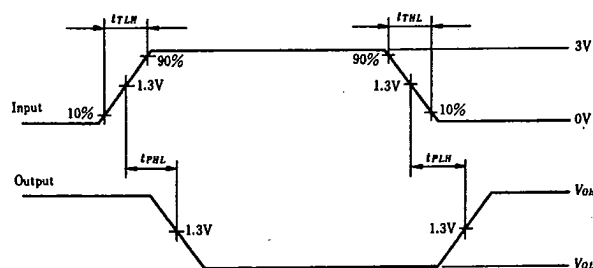
Item	Symbol	Test Conditions	min	typ	max	Unit
Propagation delay time	t_{PLH}	$V_{CC}=5\text{V}, T_a=25^\circ\text{C}, R_L=2\text{k}\Omega, C_L=15\text{pF}$	—	20	—	ns
	t_{PHL}		—	12	—	
	t_{PLH}	$V_{CC}=5 \pm 0.5\text{V}, T_a=-20 \sim +75^\circ\text{C}, R_L=2\text{k}\Omega, C_L=50\text{pF}$	20	—	54	
	t_{PHL}		8	—	28	

TESTING METHOD

Test Circuit

Note: C_L includes probe and jig capacitance.

Waveform

Input pulse: $t_{PLH} \leq 6\text{ns}, t_{PHL} \leq 6\text{ns}, \text{PRR} = 1\text{MHz}, \text{duty cycle } 50\%$